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	INFORMATION D	ISCLO	SURE	Application Number	10/771,628	
	STATEMENT BY	APPLI	CANT	Filing Date	02/03/2004	
	Data Cubaditadi In		2006	First Named Inventor	M. Brandon Steele	
	Date Submitted: Jar	nuary 2	20, 2005	Group Art Unit	2812	
	(use as many sheets	s as n <u>e</u>	cessary)	Examiner Name		
Sheet	1	of	2	Attorney Docket Number	023228-0109	

ſ	. U.S. PATENT DOCUMENTS										
ľ	Examiner	Cite	U.S. Patent D		Name of Patentee or Applicant of	Date of Publication of	Pages, Columns, Lines, Where Relevant				
1	Initials*	No.1	Number	Kind Code ² (if known)	Cited Document	Cited Document MM-DD-YYYY	Passages or Relevant Figures Appear				
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mw		EP	1039227		Meritor Heavy Vehicle Sys			į
mw		EP	1304463		General Electric			<u> </u>
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Examiner Signature	meagan S. Walling	Date Considered	9/13/05

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1 Unique citation designation number. 2See attached Kinds of U.S. Patent Documents, 2Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. Applicant is to place a check mark here if English language Translation is attached.

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Substitute for form 1449B/PTO Complete if Known 10/771.628 INFORMATION DISCLOSURE **Application Number** 02/03/2004 STATEMENT BY APPLICANT Filing Date M. Brandon Steele First Named Inventor Date Submitted: January 20, 2005 Group Art Unit 2812 (use as many sheets as necessary) **Examiner Name** 023228-0109 2 of 2 Attorney Docket Number Sheet

		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.	Τ ⁶
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Examiner Meagar S-Walling Date 9/13/05

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Date Submitted: October 22, 2004

(use as many sheets as necessary)

1 of 3

Complete if Known						
Application Number	10/771,628					
Filing Date	February 3, 2004					
First Named Inventor	M. Brandon Steele					
Group Art Unit	2812					
Examiner Name						
Attorney Docket Number	023228-0109					

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Examiner Initials*	Cite No.1	U.S. Patent D	Code ² (If known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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Examiner Signature	meagan S. Wales	Date Considered	9/13/05

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	Substitute f	or form 1449B	/PTO		Complete if Known		
	INFORMAT	ION DISCLO	SURE	Application Number	10/771,628		
STATEMENT BY APPLICANT				Filing Date	February 3, 2004		
	Date Submitte	d: Ostobor 1	22 2004	First Named Inventor	M. Brandon Steele		
	Date Sublinite	ed. October 2	22, 2004	Group Art Unit	2812		
	(use as many	sheets as ne	cessary)	Examiner Name			
Sheet	2	of	3	Attorney Docket Number	023228-0109		

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Examiner Initials*	Cite No. ¹	F Office	oreign Patent [3 Number ⁴	ocument Kind Code ⁵ (if known)	Name of Patentee or Applicant of Cited Documents	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Т6
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